Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/602,848	TANAKA ET AL.
Examiner	Art Unit

2871

Wen-Ying P. Chen

SEARCHED					
Class	Subclass	Date	Examiner		
349	40	4/10/2006	WPC		
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INTERFERENCE SEARCHED				
Class	Subclass	Date ·	Examiner	
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	DATE	EXMR
Citations search of relevant references	4/10/2006	WPC
class 349/149,152,147 combined with key words search of all databases in EAST	4/10/2006	WPC
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